Notice of References Cited

Application/Control No. 10/628,822	Applicant(s)/Pater Reexamination WALKER ET AL.		
Examiner	Art Unit		
SIUM LEE	2611	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,741,834	05-2004	Godwin, John P.	455/3.01
*	В	US-5,797,087	08-1998	Lee, Hyo Chan	455/181.1
*	υ	US-6,181,921	01-2001	Konisi et al.	455/186.2
*	D	US-2004/0198389	10-2004	Alcock et al.	455/456.1
*	Е	US-6,829,475	12-2004	Lee et al.	455/419
*	F	US-2004/0192189	09-2004	Yuhara et al.	455/003.02
*	G	US-5,732,338	03-1998	Schwob, Pierre R.	455/158.5
*	Н	US-4,392,247	07-1983	van Deursen, Theodorus H. M.	455/161.2
*	-	US-5,819,166	10-1998	Kimura et al.	455/186.1
*	J	US-6,163,683	12-2000	Dunn et al.	455/151.1
*	К	US-2004/0121748	06-2004	Glaza, Mark J.	455/151.1
*	L	US-6,122,493	09-2000	Kobayashi et al.	455/193.1
*	М	US-2003/0040272	02-2003	Lelievre et al.	455/3.06

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	т					

NON-PATENT DOCUMENTS

Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U w Х

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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